

**Amendments to the Specification:**

Please replace the Abstract, the paragraph on page 17 beginning below the subheading “ABSTRACT OF THE DISCLOSURE”, with the following rewritten paragraph:

A control circuit for testing a memory control module is provided. The memory control module that includes first and second memory blocks. The control circuit includes a processing unit and a control chip. The processing unit executes a memory testing program specific to the first memory block, and asserts data read/write commands. The control chip is in communication with the processing unit and the memory control module, and accesses to the first and second memory blocks of the memory control module for test in response to the data read/write commands in first and second states, respectively. A mapping circuit and one or more selected address lines between the control chip and the memory control module are used to switch the states of the data read/write commands.